

ECE 371

Materials and Devices

11/7/19 - Lecture 20

Space Charge Width, Reverse Bias, Capacitance

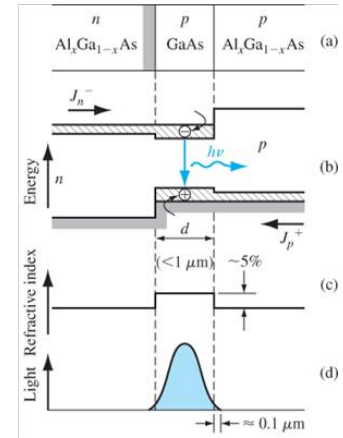
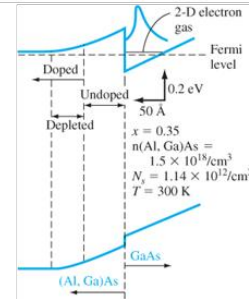
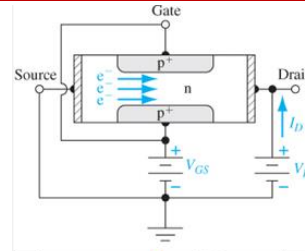
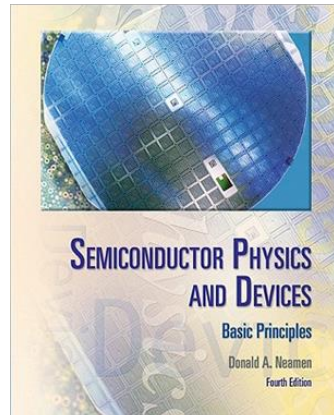
General Information

- Homework 6 due today before class
- Homework 7 assigned and due Thursday 11/21
- I will post solutions to midterm 2 later today
- If there are midterm grading questions, please follow this process:
 1. Review my solutions to compare your response to what I was looking for.
 2. If reviewing the solutions does not resolve your grading question, please see Hasan.
 3. If grading questions still cannot be resolved with Hasan, please see me.
- Reading for next time: 7.3, 7.4, 8.1

Spring 2020: ECE 471 – Materials and Devices II

Location and Time: EECE-218, Tu-Th 9:30 – 10:45 am

Prerequisites: ECE 371 (or permission of instructor)



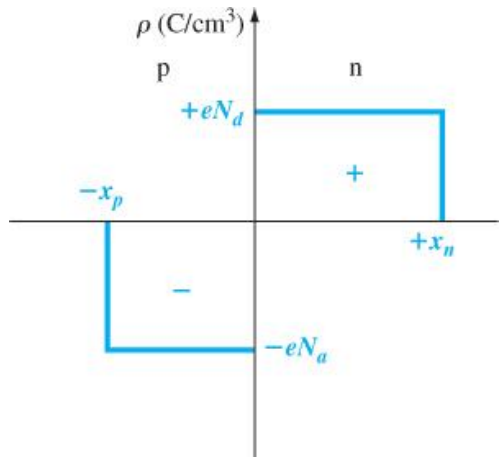
UNM Catalog Description:

An intermediate study of semiconductor materials, energy band structure, p-n junctions, ideal and non-ideal effects in field effect and bipolar transistors.

Content Details:

The course will cover portions of chapters 6, 9, and 10-14 from *Semiconductor Physics and Devices* by Donald Neamen. Some of the covered topics will include: carrier generation and recombination, carrier lifetime, ambipolar transport, quasi-Fermi levels, traps, non-ideal effects, junction breakdown, diffusion capacitance, Schottky barrier diodes, ohmic contacts, heterostructures, device physics of MOSFETs, BJTs, HEMTs, and JFETs, tunnel diodes, small-signal equivalent circuits, brief introduction to optical materials and devices (solar cells, photodetectors, LEDs, lasers).

Space Charge Width



- Depletion splits between the n and p sides and the splitting ratio depends upon the doping
- For an asymmetric junction, most of the space charge width occurs on the lightly doped side
- Total charge on each side must be equal ($N_a x_p = N_d x_n$)

space charge width on n side

$$x_n = \left[\frac{2\epsilon_s V_{bi}}{e} \left(\frac{N_a}{N_d} \right) \frac{1}{N_a + N_d} \right]^{\frac{1}{2}}$$

space charge width on p side

$$x_p = \left[\frac{2\epsilon_s V_{bi}}{e} \left(\frac{N_d}{N_a} \right) \frac{1}{N_a + N_d} \right]^{\frac{1}{2}}$$

total space charge width

$$W = x_n + x_p = \left[\frac{2\epsilon_s V_{bi}}{e} \frac{N_a + N_d}{N_a N_d} \right]^{\frac{1}{2}}$$

Test Your Understanding 7.1

TYU 7.1 Calculate V_{bi} , x_n , x_p , W , and $|E_{\max}|$ for a silicon pn junction at zero bias and $T = 300$ K for doping concentrations of (a) $N_a = 2 \times 10^{17} \text{ cm}^{-3}$, $N_d = 10^{16} \text{ cm}^{-3}$ and (b) $N_a = 4 \times 10^{15} \text{ cm}^{-3}$, $N_d = 3 \times 10^{16} \text{ cm}^{-3}$.

[Ans. (a) $V_{bi} = 0.772 \text{ V}$, $x_n = 0.3085 \mu\text{m}$, $x_p = 0.0154 \mu\text{m}$, $W = 0.3240 \mu\text{m}$, $|E_{\max}| = 4.77 \times 10^4 \text{ V/cm}$; (b) $V_{bi} = 0.699 \text{ V}$, $x_n = 0.0596 \mu\text{m}$, $x_p = 0.4469 \mu\text{m}$, $|E_{\max}| = 2.76 \times 10^4 \text{ V/cm}$, $W = 0.5064 \mu\text{m}$, $|E_{\max}| = 2.76 \times 10^4 \text{ V/cm}$]

Reverse Bias

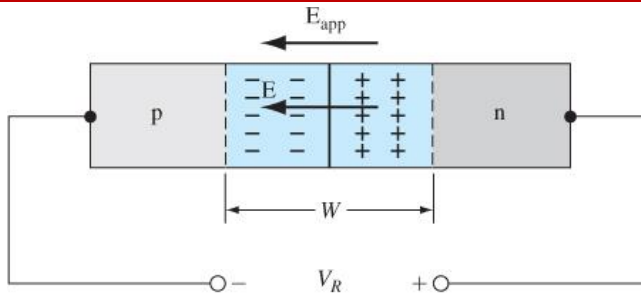


Figure 7.8 | A pn junction, with an applied reverse-biased voltage, showing the directions of the electric field induced by V_R and the space charge electric field.

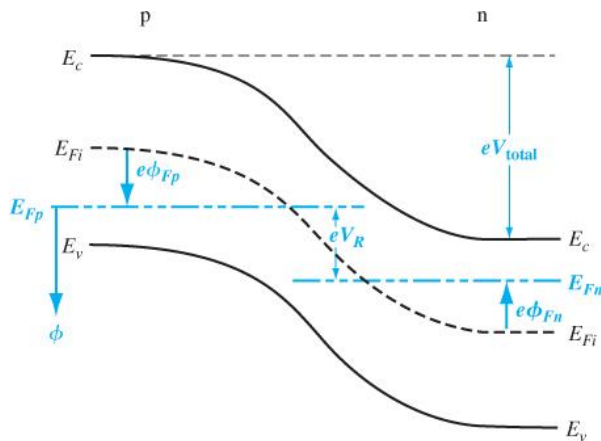


Figure 7.7 | Energy-band diagram of a pn junction under reverse bias.

- Apply + potential to n-side relative to p-side
- Potential on n-side is raised relative to p-side
- $V_{total} = V_{bi} + V_R$ *reverse bias (will be positive)*
- Assume applied voltage (V_R) is entirely dropped across the depletion region
- E-field in depletion region increases
- **Depletion width (W) also increases**
- Non-thermal-equilibrium \Rightarrow Fermi level not constant anymore
- E_{Fn} and E_{Fp} are “quasi-Fermi levels”

Reverse Bias Equations

- In all previous equations containing V_{bi} , we can simply replace V_{bi} with $V_{bi} + V_R$
- This is justified since the analysis of $E(x)$ and $\phi(x)$ are still the same, only with larger x_n and x_p now

depletion width has increased

$$E(x) = \frac{-eN_a}{\epsilon_s} (x + x_p) \text{ for } -x_p \leq x \leq 0$$

$$W = x_n + x_p = \left[\frac{2\epsilon_s(V_{bi} + V_R)}{e} \frac{N_a + N_d}{N_a N_d} \right]^{\frac{1}{2}}$$

$$E(x) = \frac{-eN_d}{\epsilon_s} (x_n - x) \text{ for } 0 \leq x \leq x_n$$

$$E_{max} = - \left[\frac{2e(V_{bi} + V_R)}{\epsilon_s} \frac{N_a N_d}{N_a + N_d} \right]^{\frac{1}{2}}$$

$$x_n = \left[\frac{2\epsilon_s(V_{bi} + V_R)}{e} \left(\frac{N_a}{N_d} \right) \frac{1}{N_a + N_d} \right]^{\frac{1}{2}}$$

$$E_{max} = \frac{-2(V_{bi} + V_R)}{W}$$

$$x_p = \left[\frac{2\epsilon_s(V_{bi} + V_R)}{e} \left(\frac{N_d}{N_a} \right) \frac{1}{N_a + N_d} \right]^{\frac{1}{2}}$$

Depletion Junction Capacitance

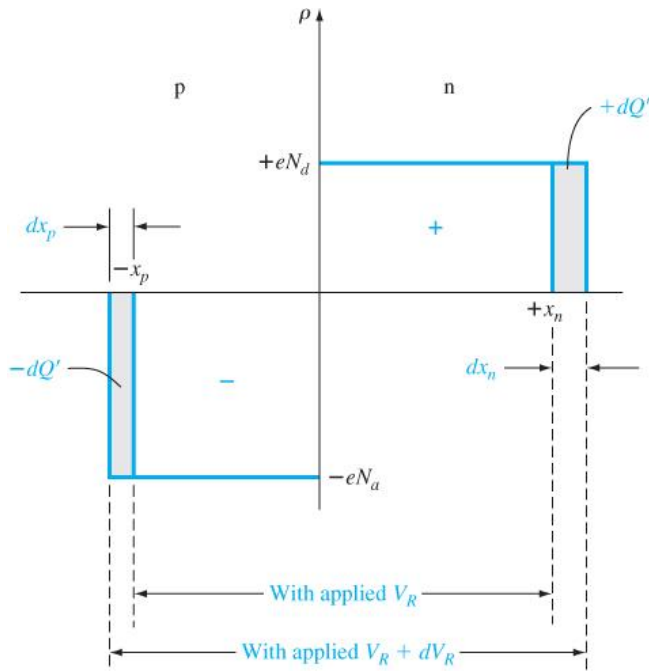


Figure 7.9 | Differential change in the space charge width with a differential change in reverse-biased voltage for a uniformly doped pn junction.

reverse bias increases
capacitance decreases

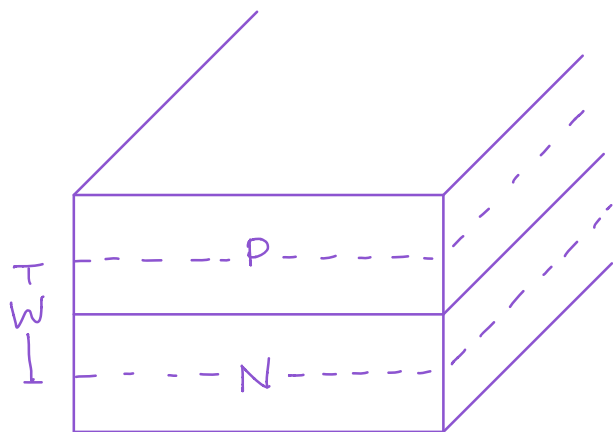
- Separation of + and – charges \Rightarrow junction capacitance
- Similar to parallel plate capacitor
- Increasing reverse bias by dV_R uncovers additional charges

$$C' = \frac{dQ'}{dV_R} = \left[\frac{e\epsilon_s N_a N_d}{2(V_{bi} + V_R)(N_a + N_d)} \right]^{\frac{1}{2}} = \frac{\epsilon_s A}{w}$$

*Depletion layer capacitance per unit area, units are [F/cm²]

- If the cross-sectional area of the junction is known, the true capacitance is

$$C = C' * A$$



CV Measurement on One-Sided Junction

- A one-sided junction can be used to determine the built-in voltage and doping concentration
- Imagine a one-sided junction with $N_a \gg N_d$ and $W \approx x_n$

- Plot $\left(\frac{1}{C'}\right)^2$ vs V_R

$$C' \approx \left[\frac{e\epsilon_s N_d}{2(V_{bi} + V_R)} \right]^{\frac{1}{2}}$$

only dependent on low doped side

$$\left(\frac{1}{C'}\right)^2 = \frac{2(V_{bi} + V_R)}{e\epsilon_s N_d}$$

$$= \frac{2}{e\epsilon_s N_d} V_R + \frac{2}{e\epsilon_s N_d} V_{bi}$$

↑
slope

↑
intercept

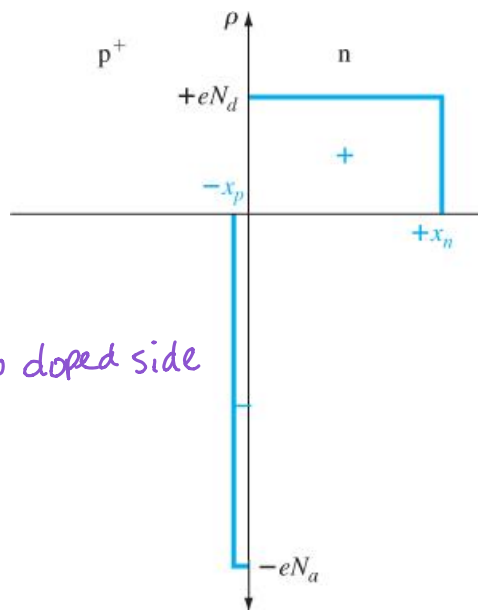


Figure 7.10 | Space charge density of a one-sided p-n junction.

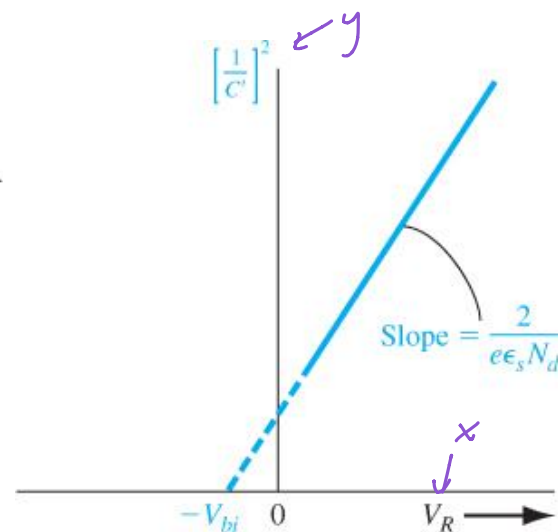


Figure 7.11 | $(1/C')^2$ versus V_R of a uniformly doped pn junction.

know N_d & slope from graph, can

find V_R and can get V_{bi} from intercept

Biased pn Junctions

- No current due to potential barrier
- E is all built in to junction

- Potential barrier increases
- Still no current
- E increases
- Fermi levels separate

- Potential barrier decreases
- E decreases
- Electrons and holes diffuse across junction
- Current flows

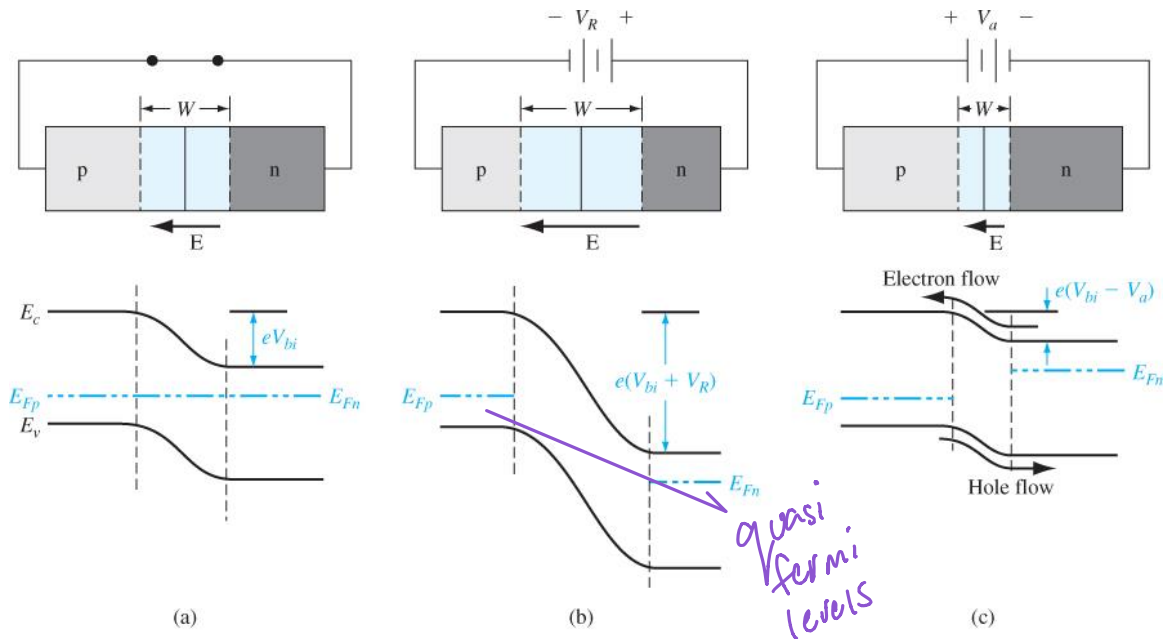


Figure 8.1 | A pn junction and its associated energy-band diagram for (a) zero bias, (b) reverse bias, and (c) forward bias.